



FDP6676S / FDB6676S

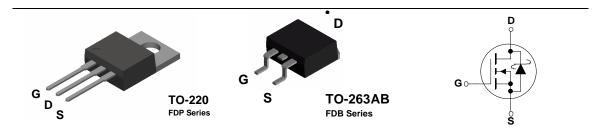
30V N-Channel PowerTrench[®] SyncFET[™]

General Description

This MOSFET is designed to replace a single MOSFET and parallel Schottky diode in synchronous DC:DC power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low $R_{DS(ON)}$ and low gate charge. The FDP/B6676S includes an integrated Schottky diode using Fairchild's monolithic SyncFET technology. The performance of the FDP/B6676S as the low-side switch in a synchronous rectifier is indistinguishable from the performance of the FDP/B6676 in parallel with a Schottky diode.

Features

- 38 A, 30 V. $R_{DS(ON)} = 6.5 \text{ m}\Omega @ V_{GS} = 10 \text{ V}$ $R_{DS(ON)} = 8.0 \text{ m}\Omega @ V_{GS} = 4.5 \text{ V}$
- Includes SyncFET Schottky body diode
- Low gate charge (40nC typical)
- High performance trench technology for extremely low R_{DS(ON)} and fast switching
- High power and current handling capability



Absolute Maximum Ratings T_A=25°C unless otherwise noted

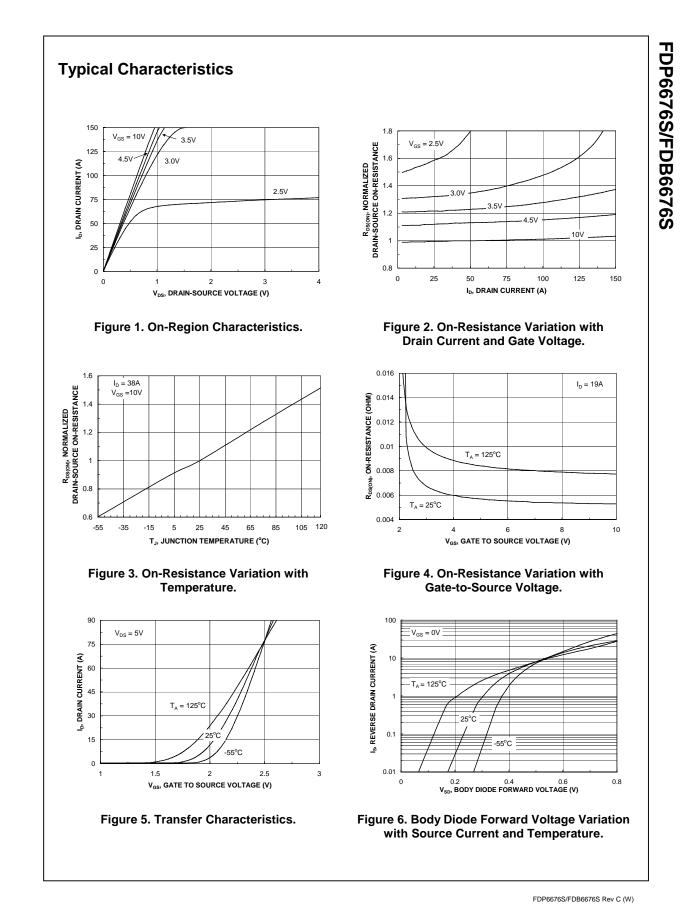
Symbol	Parameter			Ratings	Units	
V _{DSS}	Drain-Sour	ce Voltage		30	V	
V _{GSS}	Gate-Source	e Voltage		±16	V	
l _D	Drain Current – Continuous (Note 1)		(Note 1)	76	A	
		 Pulsed 	(Note 1)	150		
PD	Total Power Dissipation @ T _c = 25°C			70	W	
	Derate above 25°C			0.56	W/°C	
T _J , T _{STG}	Operating a	and Storage Junction T	emperature Range	–55 to +150 °		
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds			275	°C	
Therma	l Charac	teristics				
R _{θJC}	Thermal Resistance, Junction-to-Case			1.8	°C/W	
R _{θJA}	Thermal Resistance, Junction-to-Ambient			55	°C/W	
		g and Orderin				
Device Marking		Device	Reel Size	Tape width	Quantity	
FDB6676S		FDB6676S	13"	24mm	800	
TDDC		FDP6676S	Tube	n/a	45	

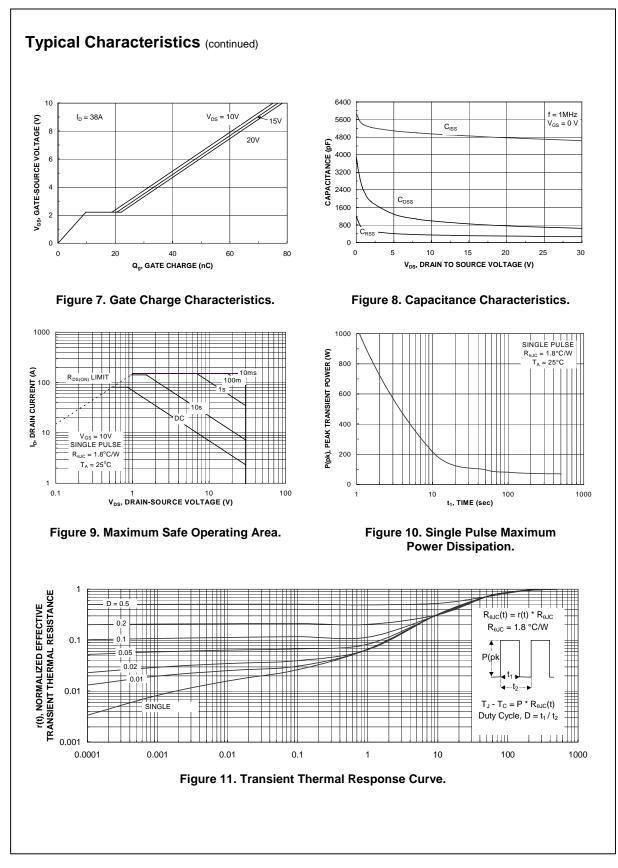
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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-So	burce Avalanche Ratings (Note	2)				I
W _{DSS}	Drain-Source Avalanche Energy	Single Pulse, $V_{DD} = 25 \text{ V}$, $I_D = 12 \text{ A}$			310	mJ
AR	Drain-Source Avalanche Current				12	Α
Off Char	acteristics					
BV _{DSS}	Drain–Source Breakdown Voltage	$V_{GS} = 0 V, I_D = 1 mA$	30			V
<u>ΔBV_{DSS}</u> ΔTj	Breakdown Voltage Temperature Coefficient	$I_D = 1$ mA, Referenced to 25°C		25		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}} = 24 \text{ V}, \qquad V_{\text{GS}} = 0 \text{ V}$			500	μA
IGSSF	Gate-Body Leakage, Forward	$V_{GS} = 16 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
	Gate-Body Leakage, Reverse	$V_{GS} = -16 V$ $V_{DS} = 0 V$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 1 \text{ mA}$	1	1.3	3	V
$\Delta V_{GS(th)}$ ΔT_J	Gate Threshold Voltage Temperature Coefficient	$I_D = 1$ mA, Referenced to 25°C		-8.4		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance			4.7 5.2 7.3	6.5 8.0 11	mΩ
D(on)	On-State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 10 \text{ V}$	60			Α
g fs	Forward Transconductance	$V_{DS} = 10 \text{ V}, \qquad I_D = 38 \text{ A}$		145		S
Dvnamio	Characteristics	-				
C _{iss}	Input Capacitance	$V_{DS} = 15 V$, $V_{GS} = 0 V$,		4853		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		850		pF
C _{rss}	Reverse Transfer Capacitance			316		pF
Switchir	g Characteristics (Note 2)			1	1	
t _{d(on)}	Turn–On Delay Time	$V_{DS} = 15 V$, $I_D = 1 A$,		14	25	ns
t _r	Turn–On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		11	20	ns
t _{d(off)}	Turn–Off Delay Time			89	142	ns
t _f	Turn–Off Fall Time			31	50	ns
Qg	Total Gate Charge	$V_{DS} = 15 V$, $I_{D} = 38 A$,		40	56	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 5 V$		10		nC
Q _{gd}	Gate-Drain Charge			11		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
V _{SD}	Drain–Source Diode Forward Voltage	$\begin{array}{c} V_{GS} = 0 \ V, I_S = 3.5 \ A \\ V_{GS} = 0 \ V, I_S = 7 \ A \end{array} (Note 1) \\ (Note 1) \end{array}$		0.4 0.5	0.7	V
t _{rr}	Diode Reverse Recovery Time	I _F = 3.5 A,		28.5		nS
Q _{rr}	Diode Reverse Recovery Charge	$d_{iF}/d_t = 300 \text{ A}/\mu \text{s}$ (Note 2)		57		nC

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Typical Characteristics (continued)

SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 FDP6676S.

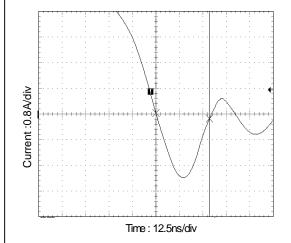
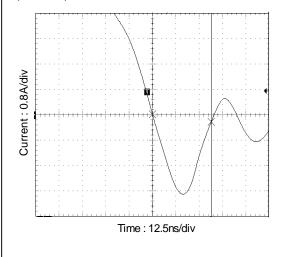


Figure 12. FDP6676S SyncFET body diode reverse recovery characteristic.

For comparison purposes, Figure 13 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDP6676).





Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

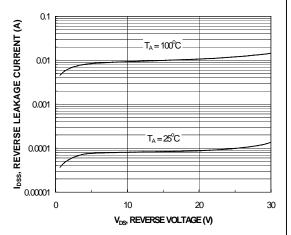


Figure 14. SyncFET diode reverse leakage versus drain-source voltage and temperature.

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